

S-5715 Series

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HIGH-SPEED / MIDDLE-SPEED LOW CURRENT CONSUMPTION BOTH POLES / UNIPOLAR DETECTION TYPE HALL IC

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The S-5715 Series, developed by CMOS technology, is a high-accuracy Hall IC that operates with high-speed / middle-speed detection and low current consumption.

The output voltage changes when the S-5715 Series detects the intensity level of flux density. Using the S-5715 Series with a magnet makes it possible to detect the open / close and rotation state in various devices.

High-density mounting is possible by using the small SOT-23-3 or the super-small SNT-4A packages.

Due to its high-accuracy magnetic characteristics, the S-5715 Series can make operation's dispersion in the system combined with magnet smaller.

Caution

This product is intended to use in general electronic devices such as consumer electronics, office equipment, and communications devices. Before using the product in medical equipment or automobile equipment including car audio, keyless entry and engine control unit, contact to ABLIC Inc. is indispensable.

■ Features

• Pole detection*1: Detection of both poles, S pole or N pole

Detection logic for magnetism*1:
 Active "L", active "H"

• Output form*1: Nch open-drain output, CMOS output

• Magnetic sensitivity: $B_{OP} = 3.0 \text{ mT typ.}$

Operating cycle (current consumption)*1:
 Product with both poles detection

$$\begin{split} t_{\text{CYCLE}} &= 0.10 \text{ ms (1400 } \mu\text{A) typ.} \\ t_{\text{CYCLE}} &= 0.90 \text{ ms (155 } \mu\text{A) typ.} \\ t_{\text{CYCLE}} &= 5.70 \text{ ms (26 } \mu\text{A) typ.} \end{split}$$

Product with S pole or N pole detection

 t_{CYCLE} = 0.05 ms (1400 μ A) typ. t_{CYCLE} = 1.25 ms (60 μ A) typ. t_{CYCLE} = 6.05 ms (13 μ A) typ.

Power supply voltage range: V_{DD} = 2.7 V to 5.5 V
 Operation temperature range: Ta = -40°C to +85°C

Lead-free (Sn 100%), halogen-free*2

*1. The option can be selected.

*2. Refer to "■ Product Name Structure" for details.

■ Applications

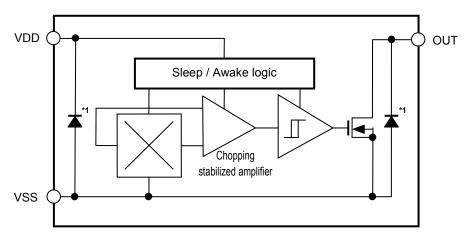
- Plaything, portable game
- Home appliance
- Housing equipment
- Industrial equipment

■ Packages

- SOT-23-3
- SNT-4A

■ Block Diagrams

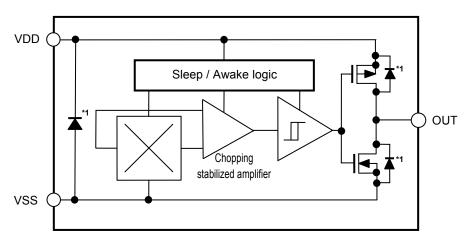
1. Nch open-drain output product



*1. Parasitic diode

Figure 1

2. CMOS output product



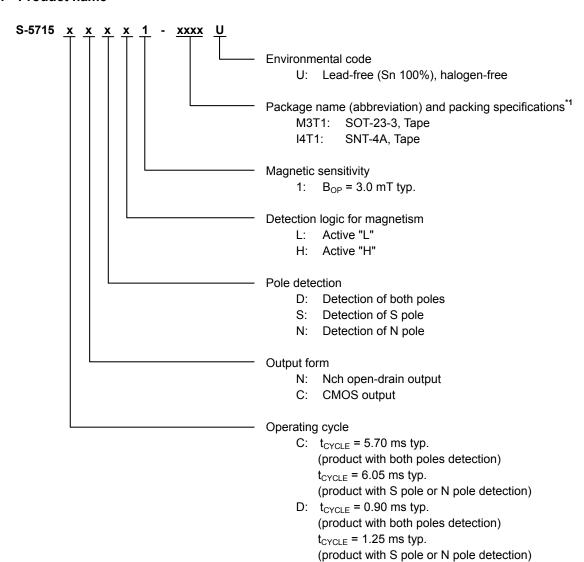
*1. Parasitic diode

Figure 2

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■ Product Name Structure

1. Product name



2. Packages

Table 1 Package Drawing Codes

E: $t_{CYCLE} = 0.10 \text{ ms typ.}$

 $t_{CYCLE} = 0.05 \text{ ms typ.}$

(product with both poles detection)

(product with S pole or N pole detection)

Package Name	Dimension	Tape	Reel	Land
SOT-23-3	MP003-C-P-SD	MP003-C-C-SD	MP003-Z-R-SD	_
SNT-4A	PF004-A-P-SD	PF004-A-C-SD	PF004-A-R-SD	PF004-A-L-SD

^{*1.} Refer to the tape drawing.

3. Product name list

3.1 SOT-23-3

3. 1. 1 Nch open-drain output product

Table 2

Product Name	Operating Cycle (t _{CYCLE})	Output Form	Pole Detection	Detection Logic for Magnetism	Magnetic Sensitivity (B _{OP})
S-5715CNDL1-M3T1U	5.70 ms	Nch open-drain output	Both poles	Active "L"	3.0 mT typ.
S-5715CNSL1-M3T1U	6.05 ms	Nch open-drain output	S pole	Active "L"	3.0 mT typ.
S-5715DNDL1-M3T1U	0.90 ms	Nch open-drain output	Both poles	Active "L"	3.0 mT typ.
S-5715DNSL1-M3T1U	1.25 ms	Nch open-drain output	S pole	Active "L"	3.0 mT typ.
S-5715ENDL1-M3T1U	0.10 ms	Nch open-drain output	Both poles	Active "L"	3.0 mT typ.
S-5715ENSL1-M3T1U	0.05 ms	Nch open-drain output	S pole	Active "L"	3.0 mT typ.
S-5715ENSH1-M3T1U	0.05 ms	Nch open-drain output	S pole	Active "H"	3.0 mT typ.

Remark Please contact our sales office for products other than the above.

3. 1. 2 CMOS output product

Table 3

Product Name	Operating Cycle (t _{CYCLE})	Output Form	Pole Detection	Detection Logic for Magnetism	Magnetic Sensitivity (B _{OP})
S-5715CCDL1-M3T1U	5.70 ms	CMOS output	Both poles	Active "L"	3.0 mT typ.
S-5715CCSL1-M3T1U	6.05 ms	CMOS output	S pole	Active "L"	3.0 mT typ.
S-5715DCDL1-M3T1U	0.90 ms	CMOS output	Both poles	Active "L"	3.0 mT typ.
S-5715DCSL1-M3T1U	1.25 ms	CMOS output	S pole	Active "L"	3.0 mT typ.
S-5715ECDL1-M3T1U	0.10 ms	CMOS output	Both poles	Active "L"	3.0 mT typ.
S-5715ECSL1-M3T1U	0.05 ms	CMOS output	S pole	Active "L"	3.0 mT typ.

Remark Please contact our sales office for products other than the above.

3. 2 SNT-4A

3. 2. 1 Nch open-drain output product

Table 4

Product Name	Operating Cycle (t _{CYCLE})	Output Form	Pole Detection	Detection Logic for Magnetism	Magnetic Sensitivity (B _{OP})
S-5715CNDL1-I4T1U	5.70 ms	Nch open-drain output	Both poles	Active "L"	3.0 mT typ.
S-5715CNSL1-I4T1U	6.05 ms	Nch open-drain output	S pole	Active "L"	3.0 mT typ.
S-5715CNNL1-I4T1U	6.05 ms	Nch open-drain output	N pole	Active "L"	3.0 mT typ.
S-5715DNDL1-I4T1U	0.90 ms	Nch open-drain output	Both poles	Active "L"	3.0 mT typ.
S-5715DNSL1-I4T1U	1.25 ms	Nch open-drain output	S pole	Active "L"	3.0 mT typ.
S-5715ENDL1-I4T1U	0.10 ms	Nch open-drain output	Both poles	Active "L"	3.0 mT typ.

Remark Please contact our sales office for products other than the above.

3. 2. 2 CMOS output product

Table 5

Product Name	Operating Cycle (t _{CYCLE})	Output Form	Pole Detection	Detection Logic for Magnetism	Magnetic Sensitivity (B _{OP})
S-5715CCDL1-I4T1U	5.70 ms	CMOS output	Both poles	Active "L"	3.0 mT typ.
S-5715CCSL1-I4T1U	6.05 ms	CMOS output	S pole	Active "L"	3.0 mT typ.
S-5715CCNL1-I4T1U	6.05 ms	CMOS output	N pole	Active "L"	3.0 mT typ.
S-5715DCDL1-I4T1U	0.90 ms	CMOS output	Both poles	Active "L"	3.0 mT typ.
S-5715DCSL1-I4T1U	1.25 ms	CMOS output	S pole	Active "L"	3.0 mT typ.
S-5715ECDL1-I4T1U	0.10 ms	CMOS output	Both poles	Active "L"	3.0 mT typ.

Remark Please contact our sales office for products other than the above.

■ Pin Configurations

1. SOT-23-3

Top view



Figure 3

Table 6

Pin No.	Symbol	Description
1	VSS	GND pin
2	VDD	Power supply pin
3	OUT	Output pin

2. SNT-4A

Top view



Figure 4

Table 7

Pin No.	Symbol	Description
1	VDD	Power supply pin
2	VSS	GND pin
3	NC ^{*1}	No connection
4	OUT	Output pin

^{*1.} The NC pin is electrically open.

The NC pin can be connected to the VDD pin or the VSS pin.

■ Absolute Maximum Ratings

Table 8

(Ta = +25°C unless otherwise specified)

	Item	Symbol	Absolute Maximum Rating	Unit
Power supply voltage		V_{DD}	$V_{SS} - 0.3$ to $V_{SS} + 7.0$	V
Output current		I _{OUT}	±2.0	mA
Nch open-drain output Output voltage product		V _{out}	$V_{SS} - 0.3$ to $V_{SS} + 7.0$	V
	CMOS output product		$V_{SS}-0.3$ to $V_{DD}+0.3$	V
Dower dissination	SOT-23-3	В	430 ^{*1}	mW
Power dissipation SNT-4A		P _D	300 ^{*1}	mW
Operation ambient temperature		T _{opr}	-40 to +85	°C
Storage temperature		T _{stg}	-40 to +125	°C

^{*1.} When mounted on board [Mounted board]

(1) Board size: $114.3 \text{ mm} \times 76.2 \text{ mm} \times t1.6 \text{ mm}$ (2) Name: JEDEC STANDARD51-7

Caution The absolute maximum ratings are rated values exceeding which the product could suffer physical damage. These values must therefore not be exceeded under any conditions.

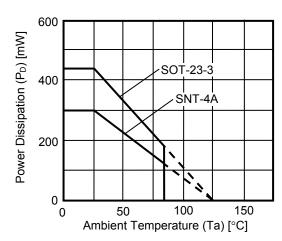


Figure 5 Power Dissipation of Package (When Mounted on Board)

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■ Electrical Characteristics

1. Product with both poles detection

1. 1 S-5715CxDxx

Table 9

(Ta = +25°C, V_{DD} = 5.0 V, V_{SS} = 0 V unless otherwise specified)

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Item	Symbol	Con	Condition		Тур.	Max.	Unit	Test Circuit
Power supply voltage	V_{DD}		_	2.7	5.0	5.5	V	_
Current consumption	I_{DD}	Average value		_	26.0	40.0	μΑ	1
		Nch open-drain output product	Output transistor Nch, I _{OUT} = 2 mA	_	_	0.4	V	2
Output voltage	V _{OUT}	CMOS sustant and dust	Output transistor Nch, I _{OUT} = 2 mA	_	_	0.4	>	2
		CMOS output product Output transistor Pch, I _{OUT} = -2 mA		V _{DD} - 0.4	-	ı	>	3
Leakage current	I _{LEAK}	Nch open-drain output pro Output transistor Nch, Vo		_	_	1	μΑ	4
Awake mode time	t _{AW}		_	_	0.10	_	ms	_
Sleep mode time	t _{SL}	_		-	5.60	_	ms	_
Operating cycle	t _{CYCLE}	t _{AW} + t _{SL}		_	5.70	12.00	ms	_

1. 2 S-5715DxDxx

Table 10

Item	Symbol	Cond	Condition		Тур.	Max.	Unit	Test Circuit
Power supply voltage	V_{DD}	-	-	2.7	5.0	5.5	V	_
Current consumption	I_{DD}	Average value		_	155.0	230.0	μΑ	1
		Nch open-drain output product	Output transistor Nch, I _{OUT} = 2 mA	_	_	0.4	٧	2
Output voltage	V _{OUT}	Output transistor Nch, I _{OUT} = 2 mA	ı	-	0.4	٧	2	
		CMOS output product Output transistor Pch, $I_{OUT} = -2 \text{ mA}$		V _{DD} - 0.4	_	I	V	3
Leakage current	I _{LEAK}	Nch open-drain output pro Output transistor Nch, V _{OL}		_	_	1	μΑ	4
Awake mode time	t _{AW}		_	_	0.10	-	ms	_
Sleep mode time	t _{SL}	_		_	0.80	1	ms	_
Operating cycle	t _{CYCLE}	t _{AW} + t _{SL}		_	0.90	2.00	ms	_

1. 3 S-5715ExDxx

Table 11

(14 120 0, 1 _{DD} 0.0 1, 1 _{SS} 0 1						000 01110		
Item	Symbol	Con	Condition		Тур.	Max.	Unit	Test Circuit
Power supply voltage	V_{DD}		_	2.7	5.0	5.5	V	_
Current consumption	I _{DD}	Average value		_	1400.0	2000.0	μΑ	1
		Nch open-drain output product	Output transistor Nch, I _{OUT} = 2 mA	_	_	0.4	>	2
Output voltage	V _{OUT}	OMOO suitsut seedust	Output transistor Nch, I _{OUT} = 2 mA	_	_	0.4	>	2
		CMOS output product Output transistor Pch, I _{OUT} = -2 mA		V _{DD} - 0.4	_	1	٧	3
Leakage current	I _{LEAK}	Nch open-drain output pro Output transistor Nch, V _O		-	_	1	μΑ	4
Awake mode time	t _{AW}		_	_	0.10	_	ms	_
Sleep mode time	t _{SL}	-		-	0.00	_	ms	-
Operating cycle	t _{CYCLE}	$t_{AW} + t_{SL}$		_	0.10	0.20	ms	_

2. Product with S pole or N pole detection

2. 1 S-5715CxSxx, S-5715CxNxx

Table 12

(Ta = +25°C, V_{DD} = 5.0 V, V_{SS} = 0 V unless otherwise specified)

	(100 100 010							
Item	Symbol	Cond	Condition		Тур.	Max.	Unit	Test Circuit
Power supply voltage	V_{DD}	-	-	2.7	5.0	5.5	V	_
Current consumption	I_{DD}	Average value		_	13.0	20.0	μΑ	1
		Nch open-drain output product	Output transistor Nch, I _{OUT} = 2 mA	_	1	0.4	>	2
Output voltage	V _{OUT}	CMOS autaut aradust	Output transistor Nch, I _{OUT} = 2 mA	-	1	0.4	>	2
		CMOS output product Output transistor Pch, $I_{OUT} = -2 \text{ mA}$		V _{DD} - 0.4	1	ı	>	3
Leakage current	I _{LEAK}	Nch open-drain output pro Output transistor Nch, V _{OL}		_	-	1	μΑ	4
Awake mode time	t _{AW}		_	_	0.05	_	ms	_
Sleep mode time	t _{SL}	_		_	6.00	_	ms	_
Operating cycle	t _{CYCLE}	t _{AW} + t _{SL}		_	6.05	12.00	ms	_

2. 2 S-5715DxSxx, S-5715DxNxx

Table 13

Item	Symbol	Condition		Min.	Тур.	Max.	Unit	Test Circuit
Power supply voltage	V_{DD}		_	2.7	5.0	5.5	V	_
Current consumption	I_{DD}	Average value		_	60.0	90.0	μА	1
		Nch open-drain output product	Output transistor Nch, I _{OUT} = 2 mA	-	1	0.4	>	2
Output voltage V _{OUT}	V _{OUT}	CMOS output product	Output transistor Nch, I _{OUT} = 2 mA	_	1	0.4	>	2
			Output transistor Pch, $I_{OUT} = -2 \text{ mA}$	V _{DD} - 0.4	-	ı	V	3
Leakage current	I _{LEAK}	Nch open-drain output pro Output transistor Nch, V _O		-	1	1	μΑ	4
Awake mode time	t _{AW}	-		_	0.05	-	ms	_
Sleep mode time	t _{SL}	-		_	1.20	ı	ms	_
Operating cycle	t _{CYCLE}	t _{AW} + t _{SL}		_	1.25	2.50	ms	_

2. 3 S-5715ExSxx, S-5715ExNxx

Table 14

Item	Symbol	Cond	Condition		Тур.	Max.	Unit	Test Circuit
Power supply voltage	V_{DD}	-	_	2.7	5.0	5.5	V	_
Current consumption	I _{DD}	Average value		_	1400.0	2000.0	μΑ	1
		Nch open-drain output product	Output transistor Nch, I _{OUT} = 2 mA	-	-	0.4	V	2
Output voltage Vo	V _{OUT}	CMOS output product	Output transistor Nch, I _{OUT} = 2 mA	-	-	0.4	V	2
			Output transistor Pch, $I_{OUT} = -2 \text{ mA}$	V _{DD} - 0.4	-	-	V	3
Leakage current	I _{LEAK}		Nch open-drain output product Output transistor Nch, V _{OUT} = 5.5 V		_	1	μА	4
Awake mode time	t _{AW}		-		0.05	_	ms	_
Sleep mode time	t _{SL}	-		_	0.00	-	ms	_
Operating cycle	t _{CYCLE}	$t_{AW} + t_{SL}$		_	0.05	0.10	ms	_

■ Magnetic Characteristics

1. Product with both poles detection

Table 15

(Ta = +25°C, V_{DD} = 5.0 V, V_{SS} = 0 V unless otherwise specified)

Item		Symbol	Condition	Min.	Тур.	Max.	Unit	Test Circuit
Operation point*1	S pole	B _{OPS}	_	1.4	3.0	4.0	mT	5
Operation point	N pole	B _{OPN}	_	-4.0	-3.0	-1.4	mT	5
Release point*2	S pole	B _{RPS}	_	1.1	2.2	3.7	mT	5
Release point	N pole	B _{RPN}	_	-3.7	-2.2	-1.1	mT	5
Hysteresis width*3	S pole	B _{HYSS}	$B_{HYSS} = B_{OPS} - B_{RPS}$	ı	0.8	ı	mT	5
nysteresis width	N pole	B _{HYSN}	$B_{HYSN} = B_{OPN} - B_{RPN} $	ı	0.8	ı	mT	5

2. Product with S pole detection

Table 16

(Ta = +25°C, V_{DD} = 5.0 V, V_{SS} = 0 V unless otherwise specified)

				, 00	, 00			/
Item		Symbol	Condition	Min.	Тур.	Max.	Unit	Test Circuit
Operation point*1	S pole	B _{OPS}	_	1.4	3.0	4.0	mT	5
Release point*2	S pole	B _{RPS}	_	1.1	2.2	3.7	mT	5
Hysteresis width*3	S pole	B _{HYSS}	$B_{HYSS} = B_{OPS} - B_{RPS}$	_	0.8	_	mT	5

3. Product with N pole detection

Table 17

(Ta = +25°C, V_{DD} = 5.0 V, V_{SS} = 0 V unless otherwise specified)

Item		Symbol	Condition	Min.	Тур.	Max.	Unit	Test Circuit
Operation point*1	N pole	B _{OPN}	_	-4.0	-3.0	-1.4	mT	5
Release point*2	N pole	B _{RPN}	_	-3.7	-2.2	-1.1	mT	5
Hysteresis width*3	N pole	B _{HYSN}	$B_{HYSN} = B_{OPN} - B_{RPN} $	-	0.8	_	mT	5

*1. B_{OPN}, B_{OPS}: Operation points

 B_{OPN} and B_{OPS} are the values of magnetic flux density when the output voltage (V_{OUT}) is inverted after the magnetic flux density applied to the S-5715 Series by the magnet (N pole or S pole) is increased (the magnet is moved closer). Even when the magnetic flux density exceeds B_{OPN} or B_{OPS} , V_{OUT} retains the status.

*2. B_{RPN}, B_{RPS}: Release points

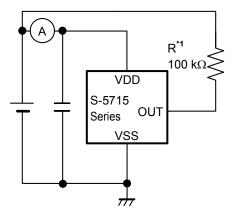
 B_{RPN} and B_{RPS} are the values of magnetic flux density when the output voltage (V_{OUT}) is inverted after the magnetic flux density applied to the S-5715 Series by the magnet (N pole or S pole) is decreased (the magnet is moved further away). Even when the magnetic flux density falls below B_{RPN} or B_{RPS} , V_{OUT} retains the status.

*3. B_{HYSN}, B_{HYSS}: Hysteresis widths

B_{HYSN} and B_{HYSS} are the difference between B_{OPN} and B_{RPN}, and B_{OPS} and B_{RPS}, respectively.

Remark The unit of magnetic density mT can be converted by using the formula 1 mT = 10 Gauss.

■ Test Circuits



*1. Resistor (R) is unnecessary for the CMOS output product.

Figure 6 Test Circuit 1

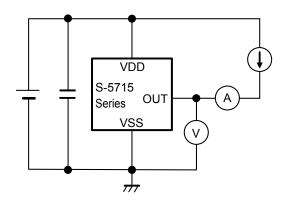


Figure 7 Test Circuit 2

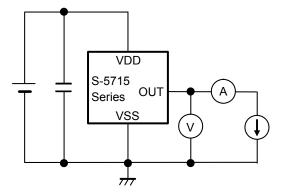


Figure 8 Test Circuit 3

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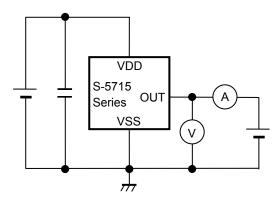
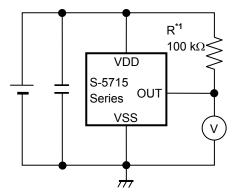


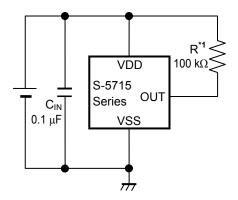
Figure 9 Test Circuit 4



*1. Resistor (R) is unnecessary for the CMOS output product.

Figure 10 Test Circuit 5

■ Standard Circuit



*1. Resistor (R) is unnecessary for the CMOS output product.

Figure 11

Caution The above connection diagram and constant will not guarantee successful operation. Perform thorough evaluation using the actual application to set the constant.

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■ Operation

1. Direction of applied magnetic flux

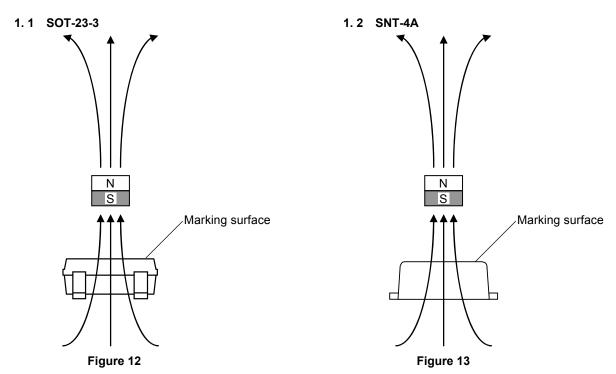
The S-5715 Series detects the flux density which is vertical to the marking surface.

In product with both poles detection, the output voltage (V_{OUT}) is inverted when the S pole or N pole is moved closer to the marking surface.

In product with S pole detection, the output voltage (V_{OUT}) is inverted when the S pole is moved closer to the marking surface.

In product with N pole detection, the output voltage (V_{OUT}) is inverted when the N pole is moved closer to the marking surface.

Figure 12 and Figure 13 show the direction in which magnetic flux is being applied.

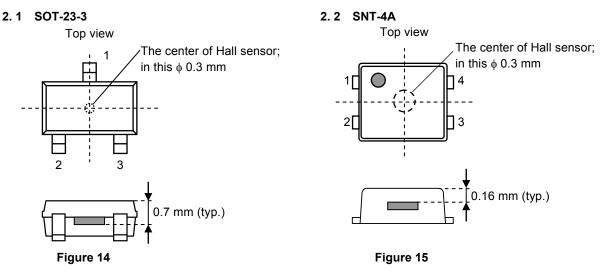


2. Position of Hall sensor

Figure 14 and Figure 15 show the position of Hall sensor.

The center of this Hall sensor is located in the area indicated by a circle, which is in the center of a package as described below.

The following also shows the distance (typ. value) between the marking surface and the chip surface of a package.



3. Basic operation

The S-5715 Series changes the output voltage level (V_{OUT}) according to the level of the magnetic flux density (N pole or S pole) applied by a magnet.

The following explains the operation when the magnetism detection logic is active "L".

3. 1 Product with both poles detection

When the magnetic flux density vertical to the marking surface exceeds B_{OPN} or B_{OPS} after the S pole or N pole of a magnet is moved closer to the marking surface of the S-5715 Series, V_{OUT} changes from "H" to "L". When the S pole or N pole of a magnet is moved further away from the marking surface of the S-5715 Series and the magnetic flux density is lower than B_{RPN} or B_{RPS} , V_{OUT} changes from "L" to "H".

Figure 16 shows the relationship between the magnetic flux density and V_{OUT}.

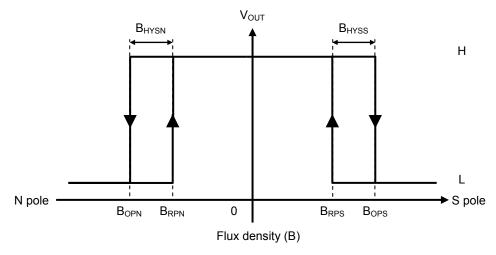


Figure 16

3. 2 Product with S pole detection

When the magnetic flux density vertical to the marking surface exceeds B_{OPS} after the S pole of a magnet is moved closer to the marking surface of the S-5715 Series, V_{OUT} changes from "H" to "L". When the S pole of a magnet is moved further away from the marking surface of the S-5715 Series and the magnetic flux density is lower than B_{RPS} , V_{OUT} changes from "L" to "H".

Figure 17 shows the relationship between the magnetic flux density and V_{OUT}.

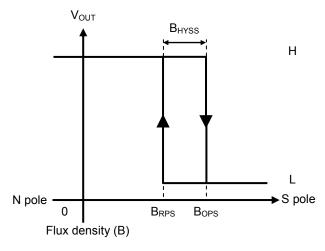


Figure 17

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3. 3 Product with N pole detection

When the magnetic flux density vertical to the marking surface exceeds B_{OPN} after the N pole of a magnet is moved closer to the marking surface of the S-5715 Series, V_{OUT} changes from "H" to "L". When the N pole of a magnet is moved further away from the marking surface of the S-5715 Series and the magnetic flux density is lower than B_{RPN} , V_{OUT} changes from "L" to "H".

Figure 18 shows the relationship between the magnetic flux density and V_{OUT}.

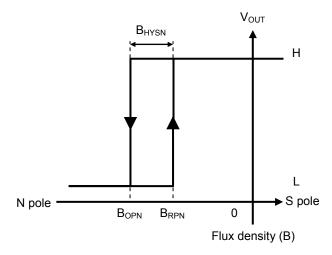


Figure 18

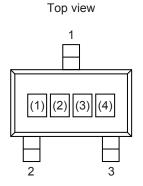
HIGH-SPEED / MIDDLE-SPEED LOW CURRENT CONSUMPTION BOTH POLES / UNIPOLAR DETECTION TYPE HALL IC S-5715 Series Rev.2.3_02

■ Precautions

- If the impedance of the power supply is high, the IC may malfunction due to a supply voltage drop caused by feed-through current. Take care with the pattern wiring to ensure that the impedance of the power supply is low.
- Note that the IC may malfunction if the power supply voltage rapidly changes.
- Do not apply an electrostatic discharge to this IC that exceeds the performance ratings of the built-in electrostatic protection circuit.
- Large stress on this IC may affect on the magnetic characteristics. Avoid large stress which is caused by bend and distortion during mounting the IC on a board or handle after mounting.
- ABLIC Inc. claims no responsibility for any disputes arising out of or in connection with any infringement by products including this IC of patents owned by a third party.

■ Marking Specifications

1. SOT-23-3



(1) to (3): Product code (Refer to **Product name vs. Product code**.)

(4): Lot number

Product name vs. Product code

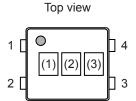
1. 1 Nch open-drain output product

Draduat Nama	Product Code			
Product Name	(1)	(2)	(3)	
S-5715CNDL1-M3T1U	Х	2	С	
S-5715CNSL1-M3T1U	Χ	2	L	
S-5715DNDL1-M3T1U	X	2	В	
S-5715DNSL1-M3T1U	Χ	2	0	
S-5715ENDL1-M3T1U	Χ	2	R	
S-5715ENSL1-M3T1U	X	2	Α	
S-5715ENSH1-M3T1U	Х	2	U	

1. 2 CMOS output product

Product Name	Product Code			
Product Name	(1)	(2)	(3)	
S-5715CCDL1-M3T1U	Х	2	М	
S-5715CCSL1-M3T1U	Χ	2	Ν	
S-5715DCDL1-M3T1U	Χ	2	Р	
S-5715DCSL1-M3T1U	Χ	2	Q	
S-5715ECDL1-M3T1U	Χ	2	S	
S-5715ECSL1-M3T1U	Х	2	Т	

2. SNT-4A



(1) to (3): Product code (Refer to **Product name vs. Product code**.)

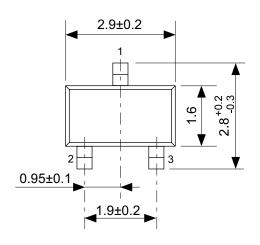
Product name vs. Product code

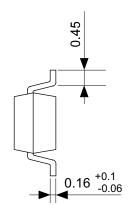
2. 1 Nch open-drain output product

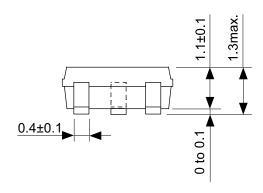
Draduat Nama	Product Code				
Product Name	(1)	(2)	(3)		
S-5715CNDL1-I4T1U	Х	2	С		
S-5715CNSL1-I4T1U	X	2	L		
S-5715CNNL1-I4T1U	Х	2	V		
S-5715DNDL1-I4T1U	Х	2	В		
S-5715DNSL1-I4T1U	Х	2	0		
S-5715ENDL1-I4T1U	Х	2	R		

2. 2 CMOS output product

Product Name		Product Code			
		(1)	(2)	(3)	
S-5715CCDL1-I4T1U		Χ	2	М	
S-5715CCSL1-I4T1U		X	2	Ζ	
S-5715CCNL1-I4T1U		Х	2	W	
S-5715DCDL1-I4T1U		Χ	2	Р	
S-5715DCSL1-I4T1U		Χ	2	Q	
S-5715ECDL1-I4T1U		X	2	S	

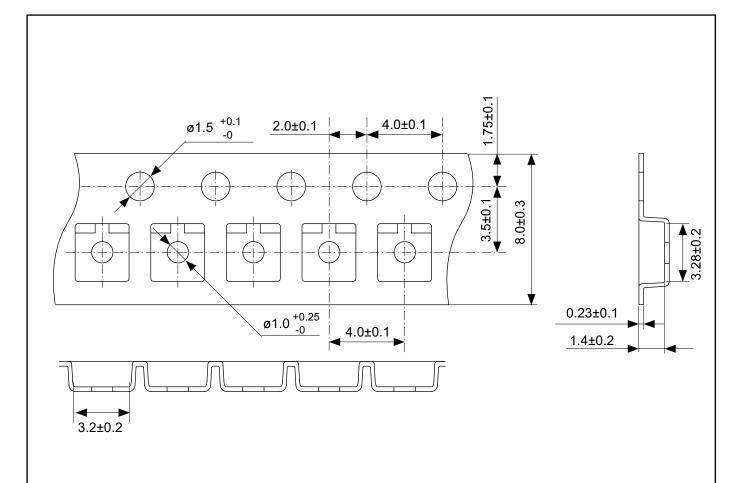


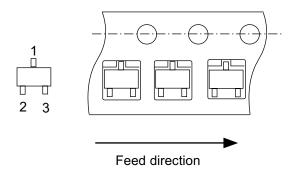




No. MP003-C-P-SD-1.1

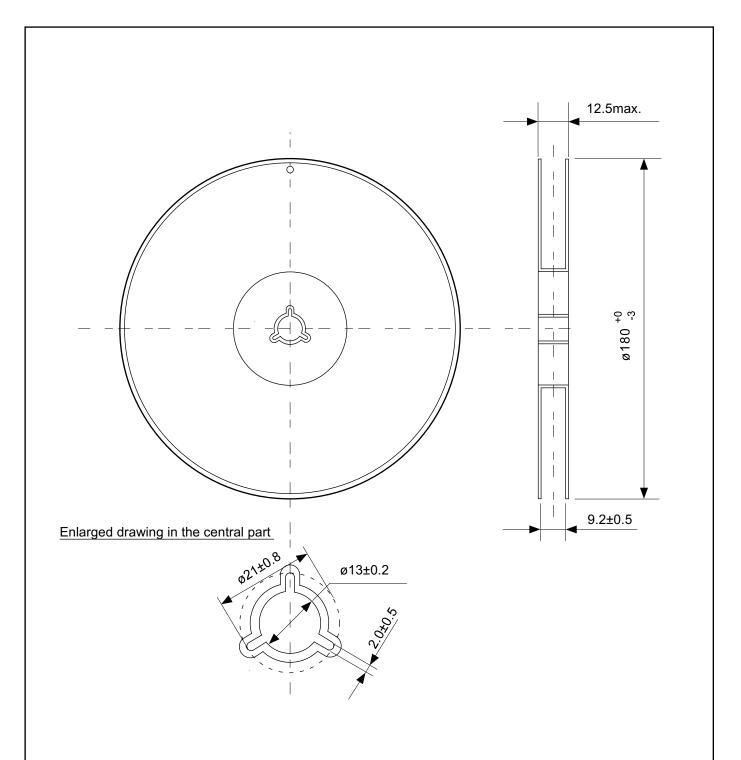
TITLE	SOT233-C-PKG Dimensions				
No.	MP003-C-P-SD-1.1				
ANGLE	\$				
UNIT	mm				
A DU LO Livia					
ABLIC Inc.					





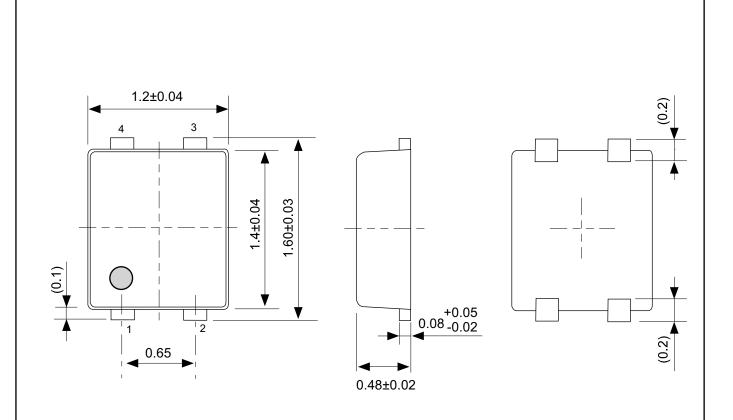
No. MP003-C-C-SD-2.0

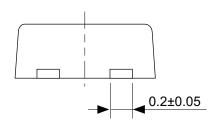
SOT233-C-Carrier Tape					
MP003-C-C-SD-2.0					
mm					
ABLIC Inc.					



No. MP003-Z-R-SD-1.0

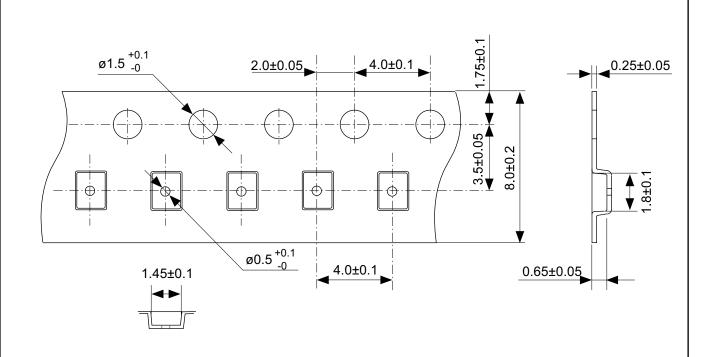
TITLE	SOT233-C-Reel					
No.	MP00	03-Z-R-SE)-1.0			
ANGLE		QTY.	3,000			
UNIT	mm					
ABLIC Inc.						

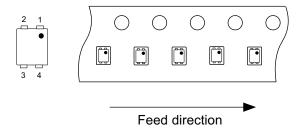




No. PF004-A-P-SD-6.0

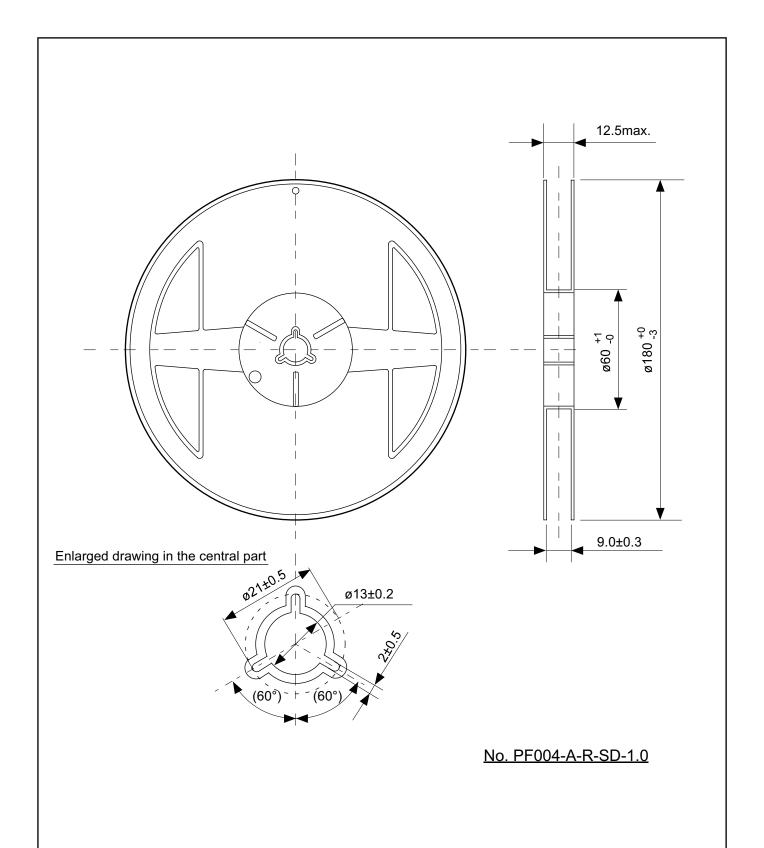
TITLE	SNT-4A-A-PKG Dimensions	
No.	PF004-A-P-SD-6.0	
ANGLE	\$ = 3	
UNIT	mm	
ABLIC Inc.		



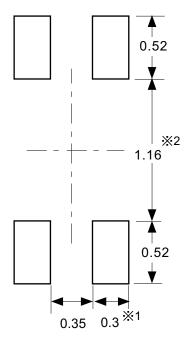


No. PF004-A-C-SD-2.0

TITLE	SNT-4A-A-Carrier Tape	
No.	PF004-A-C-SD-2.0	
ANGLE		
UNIT	mm	
ABLIC Inc.		



TITLE	SNT-4A-A-Reel		
No.	PF004-A-R-SD-1.0		
ANGLE		QTY.	5,000
UNIT	mm		
ABLIC Inc.			



- %1. ランドパターンの幅に注意してください (0.25 mm min. / 0.30 mm typ.)。 %2. パッケージ中央にランドパターンを広げないでください (1.10 mm ~ 1.20 mm)。
- 注意 1. パッケージのモールド樹脂下にシルク印刷やハンダ印刷などしないでください。
 - 2. パッケージ下の配線上のソルダーレジストなどの厚みをランドパターン表面から0.03 mm 以下にしてください。
 - 3. マスク開口サイズと開口位置はランドパターンと合わせてください。
 - 4. 詳細は "SNTパッケージ活用の手引き"を参照してください。
- ※1. Pay attention to the land pattern width (0.25 mm min. / 0.30 mm typ.).
- ※2. Do not widen the land pattern to the center of the package (1.10 mm to 1.20 mm).
- Caution 1. Do not do silkscreen printing and solder printing under the mold resin of the package.
 - 2. The thickness of the solder resist on the wire pattern under the package should be 0.03 mm or less from the land pattern surface.
 - 3. Match the mask aperture size and aperture position with the land pattern.
 - 4. Refer to "SNT Package User's Guide" for details.
- ※1. 请注意焊盘模式的宽度 (0.25 mm min. / 0.30 mm typ.)。
- ※2. 请勿向封装中间扩展焊盘模式 (1.10 mm ~ 1.20 mm)。
- 注意 1. 请勿在树脂型封装的下面印刷丝网、焊锡。
 - 2. 在封装下、布线上的阻焊膜厚度 (从焊盘模式表面起) 请控制在 0.03 mm 以下。
 - 3. 钢网的开口尺寸和开口位置请与焊盘模式对齐。
 - 4. 详细内容请参阅 "SNT 封装的应用指南"。

No. PF004-A-L-SD-4.1

TITLE	SNT-4A-A -Land Recommendation		
No.	PF004-A-L-SD-4.1		
ANGLE			
UNIT	mm		
ABLIC Inc.			

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 - The user of the products should therefore take responsibility to give thorough consideration to safety design including redundancy, fire spread prevention measures, and malfunction prevention to prevent accidents causing injury or death, fires and social damage, etc. that may ensue from the products' failure or malfunction.
 - The entire system must be sufficiently evaluated and applied on customer's own responsibility.
- 10. The products are not designed to be radiation-proof. The necessary radiation measures should be taken in the product design by the customer depending on the intended use.
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